Hybrid 7p49 Traveler

January 14, 2000

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 7P49 has die: 123-040 123-042 123-043 047-006 123-046 123-048 123-051

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 7p49 classification info. Created 20:27:55 11/14/99

Hybrid 7p49 quality: fair
Chip classification: good good good fair good good good
Bad channels (chip-channel): 3-108
Bad cells: none
Random bad capacitors: none
Channels at pedestal needed for DCMS: 35.6 35.5 33.6 37.7 34.6 35.6 36.2
```

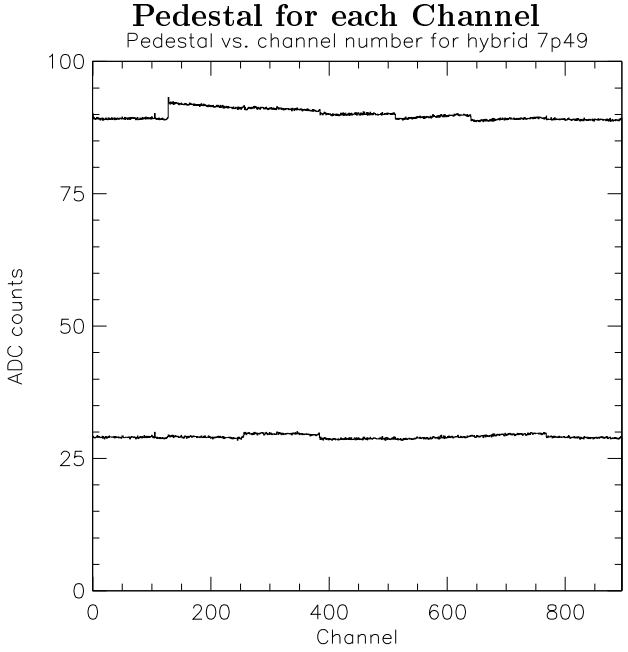
4 Comments

Chips 2, 3, and 4 replaced.
Redundant FE DVDD and DGND wirebonds.
HV test.

5 Pedestal

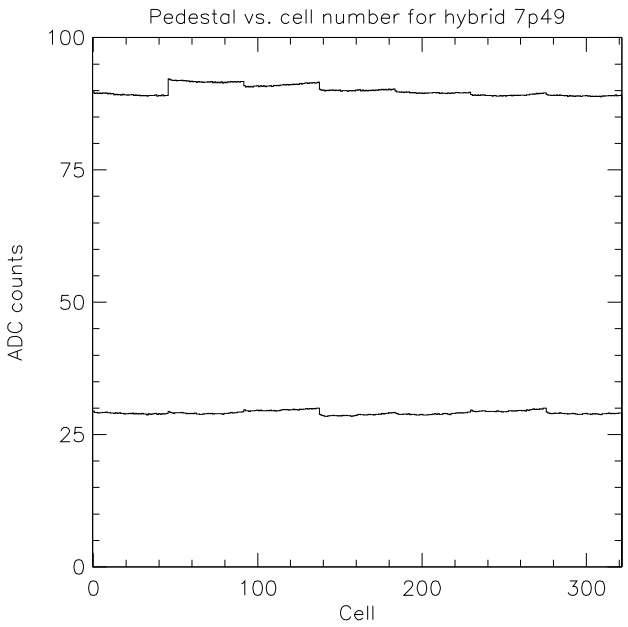
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

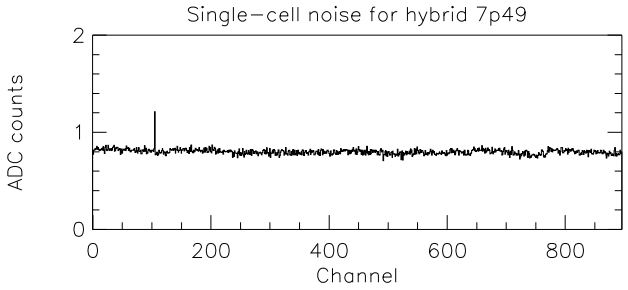
Pedestal vs. Pipeline Cell ID

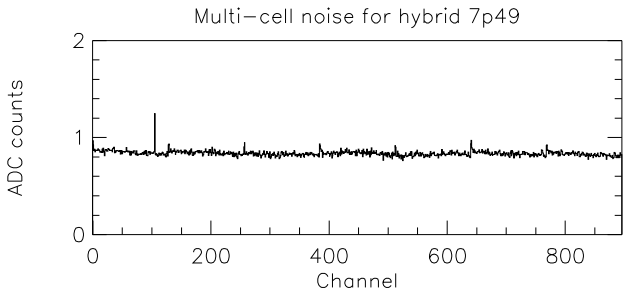


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

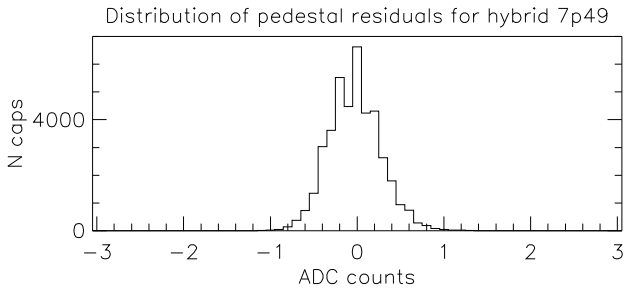
RMS Noise

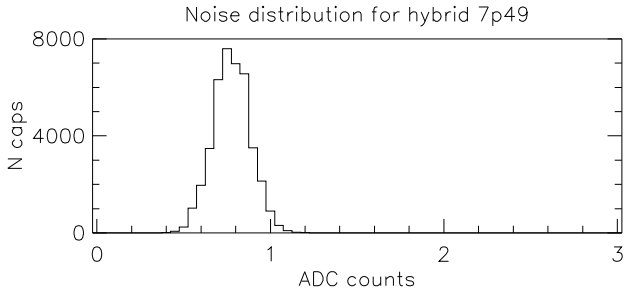




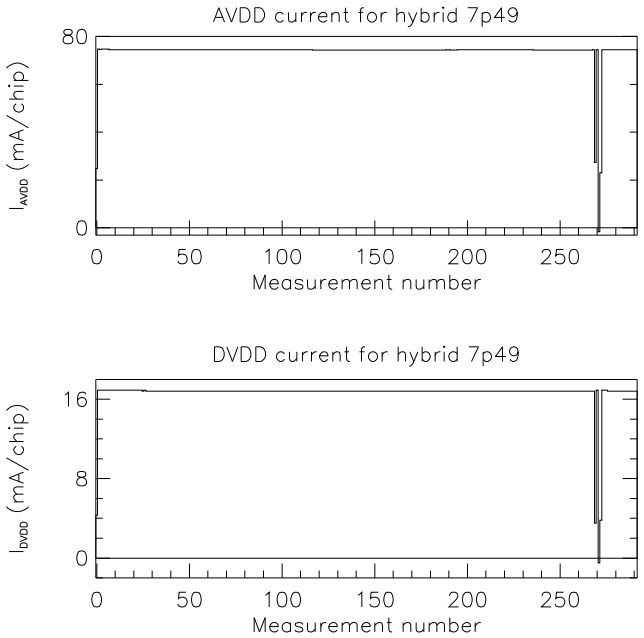
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in